Special Issue

Computer Vision and Sensing Technologies for Industrial Quality Inspection: 2nd Edition

Message from the Guest Editors

This Special Issue will include research papers reporting on cases studies of artificial intelligence techniques and will showcase the need to optimize algorithms, inference frameworks, and hardware accelerators in order to obtain good performance in quality inspection. It will mainly focus on computer vision and sensing technologies for industrial quality inspection, with possible topics including, but not limited to, imaging techniques, image processing methods, vision systems, and system optimization. Articles on industrial inspection are also welcome, on topics such as quality inspection using machine learning and data-driven methods. Submissions of review articles and original research papers are invited for this Special Issue. Keywords

- computer vision
- sensing technologies
- industrial quality inspection
- automatic optical inspection
- artificial intelligence techniques
- machine learning
- deep learning

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Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. Sensors organizes Special Issues devoted to specific sensing areas and applications each year.

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